Supplementary Information

Fabrication of silver nanoplate hierarchical turreted ordered array and its

application in trace analyses

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Fig. S1 A: The Raman mapping for the peak of 614cm⁻¹ of R6G on the 3D orderly turreted silver nanoplates array substrate over an area of 40μ m × 40μ m. (The Raman spectrometer:Renishaw inVia Reflex, the wavelength 532nm excitation light source, power: 1mW, integral time: 1 s).





Figure S2 Raman spectra for different samples (Integral time: 1s). (a): regular Raman signal of 10^{-2} M R6G solution. (b): Raman signal of 100μ l of 10^{-8} M R6G solution dropped on the silver nanoplate built hierarchical turreted ordered array with the projective area 1 cm².